

Next section presents a detailed explanation of two techniques used to determine the relative positions of atoms: X-ray diffraction and scanning probe microscopy. Scanning Tunneling Microscopy (STM) and Atomic Force Microscopy (AFM) using diffraction gratings and a simulation for the STM follow. An additional resource and the Internet can be used in conjunction with this section after all of these sections have been completed. Finally, an example of a crystal structure completes this unit.

The third section contains material that could be easily used as an integral part of a unit on crystal structure and periodicity. Before using this material, students must have a